

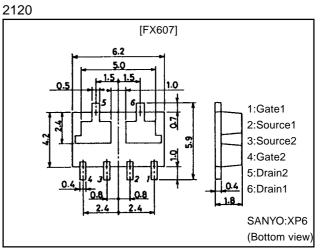
FX607 N-Channel Silicon MOSFET **Ultrahigh-Speed Switching**, **Motor Driver Applications**

Features

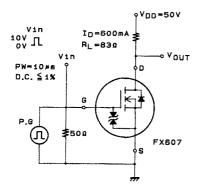
- · Composite type composed of two low ON-resistance N-channel MOSFET chips for ultrahigh-speed switching and low-voltage drive.
- · Facilitates high-density mounting.
- \cdot The FX607 is formed with two chips, each being equivalent to the 2SK2260, placed in one package.
- · Matched pair characteristics.

Package Dimensions

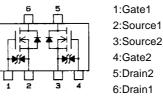
unit:mm



Switching Time Test Clrcuit



Electrical Connection



4:Gate2 5:Drain2 6:Drain1

(Top view)

Specifications

Absolute Maximum Ratings at Ta = 25°C

Parameter	Symbol	Conditions	Ratings	Unit
Drain-to-Source Voltage	V _{DSS}		150	V
Gate-to-Source Voltage	VGSS		±20	V
Drain Current (DC)	ID		1.2	А
Drain Current (Pulse)	IDP	PW≤10µs, duty cycle≤1%	4.8	А
Allowable Power Dissipation	PD	Tc=25°C, 1 unit	6	W
	PD	Mounted on ceramic board (750mm ² ×0.8mm) 1 unit	1.5	W
Total Dissipation	PT	Mounted on ceramic board (750mm ² ×0.8mm)	2	W
Channel Temperature	Tch		150	°C
Storage Temperature	Tstg		-55 to +150	°C

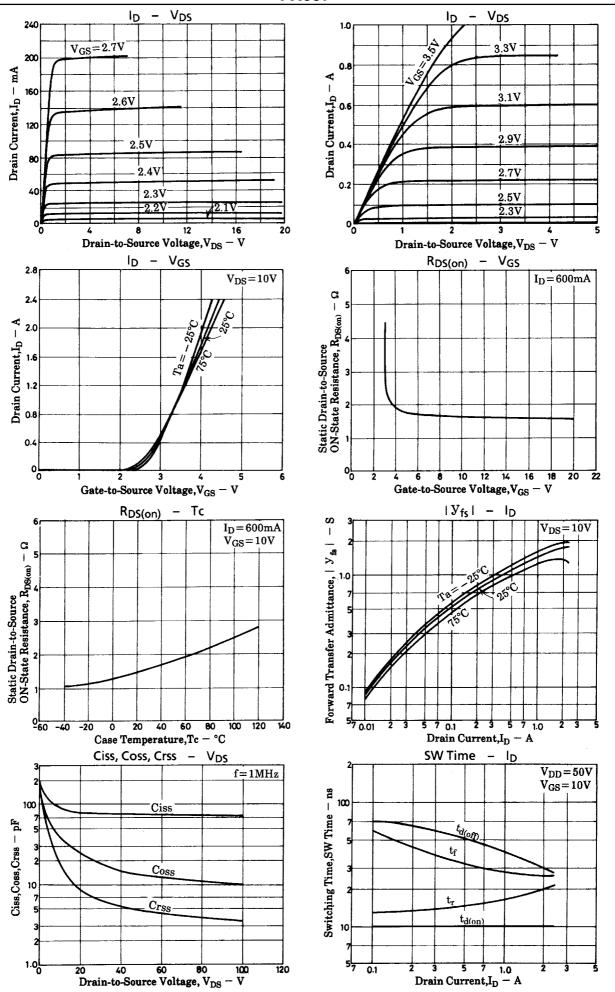
· Marking:607

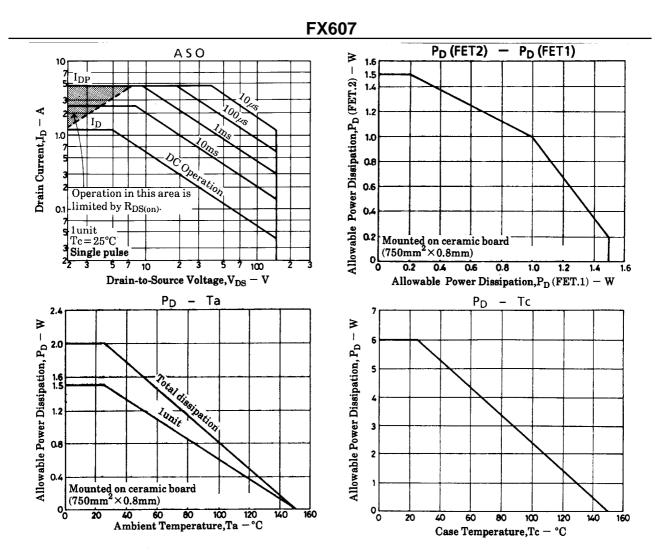
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Electrical Characteristics at Ta = 25°C

Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	Unit
D-S Breakdown Voltage	V(BR)DSS	I _D =1mA, V _{GS} =0	150			V
Zero-Gate Voltage Drain Current	IDSS	V _{DS} =150V, V _{GS} =0			100	μA
Gate-to-Source Leakage Current	IGSS	V _{GS} =±18V, V _{DS} =0			±10	μΑ
Cutoff Voltage	VGS(off)	V _{DS} =10V, ID=1mA	1.5		2.5	V
Forward Transfer Admittance	Y _{fs}	V _{DS} =10V, I _D =600mA	0.8	1.1		S
Static Drain-to-Source ON-State Resistance	R _{DS(on)}	I _D =600mA, V _{GS} =10V		1.6	2.2	Ω
Input Capacitance	Ciss	V _{DS} =20V, f=1MHz		80		pF
Output Capacitance	Coss	V _{DS} =20V, f=1MHz		25		pF
Reverse Transfer Capacitance	Crss	V _{DS} =20V, f=1MHz		8.5		pF
Turn-ON Delay Time	t _{d(on)}	See specified Test Circuit		10		ns
Rise Time	tr	See specified Test Circuit		15		ns
Turn-OFF Delay Time	td(off)	See specified Test Circuit		50		ns
Fall Time	t _f	See specified Test Circuit		30		ns
Diode Forward Voltage	V _{SD}	I _S =1.2A, V _{GS} =0		1.0		V





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